


<b>Search Notes</b>  	<b>Application/Control No.</b>  10564389	<b>Applicant(s)/Patent Under Reexamination</b>  TEEUW ET AL.
	<b>Examiner</b>  Nguyen, Phong H	<b>Art Unit</b>  3724

SEARCHED			
Class	Subclass	Date	Examiner
30	346.53, 346.54, 50	6/11/07	pn
76	104.1		

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner